

ELSEVIER

applied surface science

Author index

Al-Wazzan, R.A., J.M. Hendron and T.		Bertrand, P., see Weng, L.T.	99 (1996) 185
Morrow, Line shape study of Ba ions in		Bischoff, J.L., see Aubel, D.	99 (1996) 169
laser produced plasmas	99 (1996) 345	Björkqvist, M., see Janin, E.	99 (1996) 371
Amoddeo, A., see Chiarello, G.	99 (1996) 15	Bolmont, D., see Aubel, D.	99 (1996) 169
Aouadi, M.S., P.C. Wong and K.A.R.	27 (1270) 12	Breza, J., see Liday, J.	99 (1996) 9
Mitchell, XPS study of carbon/inconel		Brunner, R.W., see Kasrai, M.	99 (1996) 303
bilayers as a function of substrate bias	99 (1996) 319	Didina, A. W., not Rania, 141.	77 (1770) 303
Arai, M., M. Fukushima and Y. Nishiyama,		Caputi, L.S., see Chiarello, G.	99 (1996) 15
Interrupted-temperature programmed		Cassuto, A., see Colin, L.	99 (1996) 245
desorption of hydrogen over silica-sup-		Cauich, W., see Quintana, P.	99 (1996) 325
ported platinum catalysts: the distribu-		Chadwick, D., J. McAleese, K. Senkiw and	
tion of activation energy of desorption		B.C.H. Steele, On the application of	
and the phenomena of spillover and re-		XPS to ceria films grown by MOCVD	
verse spillover of hydrogen	99 (1996) 145	using a fluorinated precursor	99 (1996) 417
Asikainen, T., M. Ritala, M. Leskelä, T.		Chen, Y., see Ji, W.	99 (1996) 151
Prohaska, G. Friedbacher and M.		Cheremskoy, P.G., see Skatkov, L.I.	99 (1996) 367
Grasserbauer, AFM and STM studies on		Chiarello, G., R. Barberi, A. Amoddeo, L.S.	
In2O3 and ITO thin films deposited by		Caputi and E. Colavita, XPS and AFM	
atomic layer epitaxy	99 (1996) 91	characterization of a vanadium oxide	
Atamny, F., see Grunwaldt, JD.	99 (1996) 353	film on TiO2(100) surface	99 (1996) 15
Aubel, D., L. Kubler, J.L. Bischoff, L. Si-		Chiou, BS., see Wu, WF.	99 (1996) 237
mon and D. Bolmont, X-ray photoelec-		Colavita, E., see Chiarello, G.	99 (1996) 15
tron diffraction investigation of Ge seg-		Colin, L., A. Cassuto, J.J. Ehrhardt, M.F.	
regation and film morphology during		Ruiz-Lopez and D. Jamois, Adsorption	
first stage heteroepitaxy of Si on Ge(001)	99 (1996) 169	and decomposition of hexamethyldi-	
Augereau, F., B. Cros and J.P. Marco, Sur-		siloxane on platinum: an XPS, UPS and	
face study of cross-linking gradients in		TDS study	99 (1996) 245
photopolymers by acoustic microscopy	99 (1996) 293	Comelli, G., see Baraldi, A.	99 (1996) 1
		Crisafulli, C., S. Scirè, S. Minicò, R. Mag-	
Baiker, A., see Grunwaldt, JD.	99 (1996) 353	giore and S. Galvagno, Ru-Cu/ZSM5	
Bancroft, G.M., see Kasrai, M.	99 (1996) 303	catalysts: Characterization by FT-IR	
Banerjee, S., M.K. Sanyal and A. Datta, A		spectroscopy	99 (1996) 401
simulation study of multi-atom tips and		Cros, B., see Augereau, F.	99 (1996) 293
estimation of resolution in atomic force		Czanderna, A.W., see Jung, D.R.	99 (1996) 161
microscopy	99 (1996) 255		
Baraldi, A., L. Gregoratti, G. Comelli, V.R.		Datta, A., see Banerjee, S.	99 (1996) 255
Dhanak, M. Kiskinova and R. Rosei,		Deslandes, Y., see Spevack, P.	99 (1996) 41
CO adsorption and CO oxidation on	*******	Devillers, M., see Weng, L.T.	99 (1996) 185
Rh(100)	99 (1996) 1	Dhanak, V.R., see Baraldi, A.	99 (1996) 1
Barberi, R., see Chiarello, G.	99 (1996) 15	Diana, V.I., See Datain, 75.	27 (1720)
Bardwell, J.A., see Kasrai, M.	99 (1996) 303	Ehrhardt, J.J., see Colin, L.	99 (1996) 245
Barthés-Labrousse, M.G., see Marsh, J.	99 (1996) 335	Enmardi, J.J., See Colli, L.	99 (1990) 243
Bayrachny, B.I., see Skatkov, L.I.	99 (1996) 367		00 (1001)
Behner, H. and R. Rupp, Surface composi-		Feng, Z.C., see Li, K.	99 (1996) 59
tion of CVD-grown α-SiC layers - an	00 (1004) ==	Flodström, A.S., see Hirschauer, B.	99 (1996) 285
XPS and LEED study	99 (1996) 27	Friedbacher, G., see Asikainen, T.	99 (1996) 91



ELSEVIER

applied surface science

Author index

Al-Wazzan, R.A., J.M. Hendron and T.		Bertrand, P., see Weng, L.T.	99 (1996) 185
Morrow, Line shape study of Ba ions in		Bischoff, J.L., see Aubel, D.	99 (1996) 169
laser produced plasmas	99 (1996) 345	Björkqvist, M., see Janin, E.	99 (1996) 371
Amoddeo, A., see Chiarello, G.	99 (1996) 15	Bolmont, D., see Aubel, D.	99 (1996) 169
Aouadi, M.S., P.C. Wong and K.A.R.	27 (1270) 12	Breza, J., see Liday, J.	99 (1996) 9
Mitchell, XPS study of carbon/inconel		Brunner, R.W., see Kasrai, M.	99 (1996) 303
bilayers as a function of substrate bias	99 (1996) 319	Didina, A. W., not Rania, 141.	77 (1770) 303
Arai, M., M. Fukushima and Y. Nishiyama,		Caputi, L.S., see Chiarello, G.	99 (1996) 15
Interrupted-temperature programmed		Cassuto, A., see Colin, L.	99 (1996) 245
desorption of hydrogen over silica-sup-		Cauich, W., see Quintana, P.	99 (1996) 325
ported platinum catalysts: the distribu-		Chadwick, D., J. McAleese, K. Senkiw and	
tion of activation energy of desorption		B.C.H. Steele, On the application of	
and the phenomena of spillover and re-		XPS to ceria films grown by MOCVD	
verse spillover of hydrogen	99 (1996) 145	using a fluorinated precursor	99 (1996) 417
Asikainen, T., M. Ritala, M. Leskelä, T.		Chen, Y., see Ji, W.	99 (1996) 151
Prohaska, G. Friedbacher and M.		Cheremskoy, P.G., see Skatkov, L.I.	99 (1996) 367
Grasserbauer, AFM and STM studies on		Chiarello, G., R. Barberi, A. Amoddeo, L.S.	
In2O3 and ITO thin films deposited by		Caputi and E. Colavita, XPS and AFM	
atomic layer epitaxy	99 (1996) 91	characterization of a vanadium oxide	
Atamny, F., see Grunwaldt, JD.	99 (1996) 353	film on TiO2(100) surface	99 (1996) 15
Aubel, D., L. Kubler, J.L. Bischoff, L. Si-		Chiou, BS., see Wu, WF.	99 (1996) 237
mon and D. Bolmont, X-ray photoelec-		Colavita, E., see Chiarello, G.	99 (1996) 15
tron diffraction investigation of Ge seg-		Colin, L., A. Cassuto, J.J. Ehrhardt, M.F.	
regation and film morphology during		Ruiz-Lopez and D. Jamois, Adsorption	
first stage heteroepitaxy of Si on Ge(001)	99 (1996) 169	and decomposition of hexamethyldi-	
Augereau, F., B. Cros and J.P. Marco, Sur-		siloxane on platinum: an XPS, UPS and	
face study of cross-linking gradients in		TDS study	99 (1996) 245
photopolymers by acoustic microscopy	99 (1996) 293	Comelli, G., see Baraldi, A.	99 (1996) 1
		Crisafulli, C., S. Scirè, S. Minicò, R. Mag-	
Baiker, A., see Grunwaldt, JD.	99 (1996) 353	giore and S. Galvagno, Ru-Cu/ZSM5	
Bancroft, G.M., see Kasrai, M.	99 (1996) 303	catalysts: Characterization by FT-IR	
Banerjee, S., M.K. Sanyal and A. Datta, A		spectroscopy	99 (1996) 401
simulation study of multi-atom tips and		Cros, B., see Augereau, F.	99 (1996) 293
estimation of resolution in atomic force		Czanderna, A.W., see Jung, D.R.	99 (1996) 161
microscopy	99 (1996) 255		
Baraldi, A., L. Gregoratti, G. Comelli, V.R.		Datta, A., see Banerjee, S.	99 (1996) 255
Dhanak, M. Kiskinova and R. Rosei,		Deslandes, Y., see Spevack, P.	99 (1996) 41
CO adsorption and CO oxidation on	*******	Devillers, M., see Weng, L.T.	99 (1996) 185
Rh(100)	99 (1996) 1	Dhanak, V.R., see Baraldi, A.	99 (1996) 1
Barberi, R., see Chiarello, G.	99 (1996) 15	Dilata, V.I., See Datain, 75.	27 (1720)
Bardwell, J.A., see Kasrai, M.	99 (1996) 303	Ehrhardt, J.J., see Colin, L.	99 (1996) 245
Barthés-Labrousse, M.G., see Marsh, J.	99 (1996) 335	Enmardi, J.J., See Colli, L.	99 (1990) 243
Bayrachny, B.I., see Skatkov, L.I.	99 (1996) 367		00 (1001)
Behner, H. and R. Rupp, Surface composi-		Feng, Z.C., see Li, K.	99 (1996) 59
tion of CVD-grown α-SiC layers - an	00 (1004) ==	Flodström, A.S., see Hirschauer, B.	99 (1996) 285
XPS and LEED study	99 (1996) 27	Friedbacher, G., see Asikainen, T.	99 (1996) 91

Fukushima, M., see Arai, M.	99 (1996) 145	-4.6	
Fusy, J., see Ruby, C.	99 (1996) 393	and fluorescence measurements in Si L- and K-edge absorption spectroscopy	00 (100() 202
rusy, s., see Ruby, C.	77 (1770) 373	Kawakami, E., see Oku, T.	99 (1996) 303
	00 (100 () 101	Kawakyu, Y., see Nishibe, T.	99 (1996) 265
Galvagno, S., see Crisafulli, C.	99 (1996) 401	Keller, B.A., see Osman, M.A.	99 (1996) 35
Gerlach, J.W., see Wengenmair, H.	99 (1996) 313	Kiskinova, M., see Baraldi, A.	99 (1996) 261
Geus, J.W., see Van Wijk, R.	99 (1996) 127		99 (1996) 1
Geus, J.W., see Van Wijk, R.	99 (1996) 197	Knotter, D.M., Application and properties	
Gijzeman, O.L.J., see Van Wijk, R.	99 (1996) 127	of sub-monomolecular layers of silicon	00 (1004) 00
Gijzeman, O.L.J., see Mens, A.J.M.	99 (1996) 133	dioxide deposited under mild conditions	99 (1996) 99
Gijzeman, O.L.J., see Van Wijk, R.	99 (1996) 197	Koch, T. and P. Ziemann, Zr-silicide forma-	
Göbel, U., see Grunwaldt, JD.	99 (1996) 353	tion during the epitaxial growth of Y-	
Goldmann, A., see Kürpick, U.	99 (1996) 221	stabilized zirconia films on Si(100) and	
Gomozov, V.P., see Skatkov, L.I.	99 (1996) 367	its avoidance by ion beam assisted depo-	
Gorse, D., see Marsh, J.	99 (1996) 335	sition at a reduced temperature	99 (1996) 51
Görts, P.C., see Van Wijk, R.	99 (1996) 127	Krastev, V., see Marinova, Ts.	99 (1996) 119
Göthelid, M., see Janin, E.	99 (1996) 371	Kubler, L., see Aubel, D.	99 (1996) 169
Grasserbauer, M., see Asikainen, T.	99 (1996) 91	Kunimori, K., see Watanabe, K.	99 (1996) 411
Gregoratti, L., see Baraldi, A.	99 (1996) 1	Kürpick, U., G. Meister and A. Goldmann,	
Grehk, T.M., see Janin, E.	99 (1996) 371	Influence of oxygen on the mass diffu-	
Grunwaldt, JD., F. Atamny, U. Göbel and		sion of Ag on Cu(110): a laterally re-	
A. Baiker, Preparation of thin silver		solved photoemission study	99 (1996) 221
films on mica studied by XRD and AFM	99 (1996) 353	Laidani, N., A. Miotello and J. Perrière,	
Gui, L., see Guo, Q.	99 (1996) 229	Chemical, mechanical and electrical	
Guo, Q., L. Gui and N. Wu, CuCl growth		properties of CN,-films produced by re-	
on the reconstructed surface of (0001)		active sputtering and N*-implantation in	
haematite	99 (1996) 229	carbon films	99 (1996) 273
	,,	Lennard, W.N., see Kasrai, M.	
Heberhan EHDM and Von Wille D	00 (1004) 127		99 (1996) 303
Habraken, F.H.P.M., see Van Wijk, R. Habraken, F.H.P.M., see Van Wijk, R.	99 (1996) 127	Leskelä, M., see Asikainen, T.	99 (1996) 91
	99 (1996) 197	Li, K., J. Lin, A.T.S. Wee, K.L. Tan, Z.C.	
Hallin, C., see Marinova, Ts.	99 (1996) 119	Feng and J.B. Webb, Surface and inter-	
Hendron, J.M., see Al-Wazzan, R.A.	99 (1996) 345	face analysis of GaSb/GaAs semicon-	00 (1007) 50
Hirschauer, B., S. Söderholm, J. Paul and		ductor materials	99 (1996) 59
A.S. Flodström, Large area synthesis of	00 (1004) 205	Li, S., see Ji, W.	99 (1996) 151
thin alumina films by laser ablation	99 (1996) 285	Liday, J., S. Tomek and J. Breza, AES of	
		semi-insulating polycrystalline silicon	00/100/
Jamois, D., see Colin, L.	99 (1996) 245	layers	99 (1996) 9
Janin, E., M. Björkqvist, T.M. Grehk, M.		Lin, J., see Li, K.	99 (1996) 59
Göthelid, CM. Pradier, U.O. Karlsson		Linares-Solano, A., see Muñoz-Guillena,	
and A. Rosengren, Hydrogen adsorption		M.J.	99 (1996) 111
on the Pt(111)($\sqrt{3} \times \sqrt{3}$)R30°-Sn sur-		Maggiore, R., see Crisafulli, C.	99 (1996) 401
face alloy studied by high resolution		Marco, J.P., see Augereau, F.	99 (1996) 293
core level photoelectron spectroscopy	99 (1996) 371	Marée, C.H.M., see Van Wijk, R.	99 (1996) 127
Janzén, E., see Marinova, Ts.	99 (1996) 119	Marée, C.H.M., see Van Wijk, R.	99 (1996) 197
Ji, W., Y. Chen, S. Shen, S. Li and H.		Marinova, Ts., V. Krastev, C. Hallin, R.	
Wang, FTIR study of adsorption of CO,		Yakimova and E. Janzén, Interface	
NO and C2H4 and reaction of CO + H2		chemistry and electric characterisation	
on the well-dispersed FeOx/γ-Al ₂ O ₃		of nickel metallisation on 6H-SiC	99 (1996) 119
and FeOx/TiO2(a) catalysts	99 (1996) 151	Marsh, J., L. Minel, M.G. Barthés-	** (***** ***
Jung, D.R. and A.W. Czanderna, X-ray pho-		Labrousse and D. Gorse, The nature of	
toelectron spectroscopy of Cr/COOCH 3		the surface acidity of anodised titanium:	
interfaces on self-assembled monolayers		an XPS study using 1,2-diaminoethane	99 (1996) 335
of 16-mercaptohexadecanoate	99 (1996) 161	Matsuura, Y., see Nishibe, T.	99 (1996) 35
		McAleese, J., see Chadwick, D.	99 (1996) 417
Karlsson, U.O., see Janin, E.	99 (1996) 371	Meister, G., see Kürpick, U.	99 (1996) 221
Kasrai, M., W.N. Lennard, R.W. Brunner,	77 (1770) 311	Mens, A.J.M. and O.L.J. Gijzeman, AES	77 (1770) 221
G.M. Bancroft, J.A. Bardwell and K.H.		study of electron beam induced damage	
Tan, Sampling depth of total electron		on TiO ₂ surfaces	99 (1996) 133
in, sampling depth of total electron		on 1102 surfaces	22 (1770) 133

Minel, L., see Marsh, J.	99 (1996) 335	Rosei, R., see Baraldi, A.	99 (1996) 1
Minicò, S., see Crisafulli, C.	99 (1996) 401	Rosengren, A., see Janin, E.	99 (1996) 371
Miotello, A., see Laidani, N.	99 (1996) 273	Ruby, C. and J. Fusy, Oxidation of ultrathin	
Mitchell, K.A.R., see Aouadi, M.S.	99 (1996) 319	iron layers grown on Cu(111)	99 (1996) 393
Mitsuhashi, H., see Nishibe, T.	99 (1996) 35	Ruiz-Lopez, M.F., see Colin, L.	99 (1996) 245
Morrow, T., see Al-Wazzan, R.A.	99 (1996) 345	Rupp, R., see Behner, H.	99 (1996) 27
Muñoz-Guillena, M.J., A. Linares-Solano			
and C. Salinas-Martínez de Lecea, High		Salinas-Martínez de Lecea, C., see Muñoz-	
temperature SO ₂ retention by CaO	99 (1996) 111	Guillena, M.J.	99 (1996) 111
Murakami, M., see Oku, T.	99 (1996) 265	Sanyal, M.K., see Banerjee, S.	99 (1996) 255
		Scirè, S., see Crisafulli, C.	99 (1996) 401
Nishibe, T., H. Mitsuhashi, Y. Matsuura		Senkiw, K., see Chadwick, D.	99 (1996) 417
and Y. Kawakyu, Approach to in situ		Shen, S., see Ji, W.	99 (1996) 151
characterization of polysilicon surfaces		Silberberg, E., see Reniers, F.	99 (1996) 379
annealed by XeCl excimer laser	99 (1996) 35	Simon, L., see Aubel, D.	99 (1996) 169
Nishigaki, S., see Yamada, K.	99 (1996) 21	Skatkov, L.I., P.G. Cheremskoy, V.P. Go-	
Nishiyama, Y., see Arai, M.	99 (1996) 145	mozov and B.I. Bayrachny, Investiga-	
Norton, P.R., see Zhdanov, V.P.	99 (1996) 205	tion of the solid surface structural inho-	
		mogeneities by the 'combined' small-	
Ohnuma, H., see Watanabe, K.	99 (1996) 411	angle X-ray scattering and Hg porosime-	
Oku, T., E. Kawakami, M. Uekubo, K.		try methods	99 (1996) 367
Takahiro, S. Yamaguchi and M. Mu-		Söderholm, S., see Hirschauer, B.	99 (1996) 285
rakami, Diffusion barrier property of		Spevack, P. and Y. Deslandes, ToF-SIMS	
TaN between Si and Cu	99 (1996) 265	analysis of adsorbate/membrane inter-	
Osman, M.A. and B.A. Keller, Wettability		actions. I. Adsorption of dehydroabietic	
of native silver surfaces	99 (1996) 261	acid on poly(vinylidene fluoride)	99 (1996) 41
		Steele, B.C.H., see Chadwick, D.	99 (1996) 417
Pastuszka, S., A.S. Terekhov and A. Wolf,		Stritzker, B., see Wengenmair, H.	99 (1996) 313
'Stable to unstable' transition in the (Cs,		•	
O) activation layer on GaAs (100) sur-		Takahiro, K., see Oku, T.	99 (1996) 265
faces with negative electron affinity in		Tan, K.H., see Kasrai, M.	99 (1996) 303
extremely high vacuum	99 (1996) 361	Tan, K.L., see Li, K.	99 (1996) 59
Paul, J., see Hirschauer, B.	99 (1996) 285	Terekhov, A.S., see Pastuszka, S.	99 (1996) 361
Pedraza, F., see Vázquez, A.	99 (1996) 213	Tirions, O., see Weng, L.T.	99 (1996) 185
Peña, J.L., see Quintana, P.	99 (1996) 325	Tomek, S., see Liday, J.	99 (1996) 9
Pere, J., see Valden, M.	99 (1996) 83	Tomellini, M., Modelling of the particle	
Perrière, J., see Laidani, N.	99 (1996) 273	size distribution function in the nucle-	
Pessa, M., see Valden, M.	99 (1996) 83	ation and early stages of thin film growth	99 (1996) 67
Pomes, R., see Quintana, P.	99 (1996) 325	, , , , , , , , , , , , , , , , , , , ,	
Pradier, CM., see Janin, E.	99 (1996) 371	Uekubo, M., see Oku, T.	99 (1996) 265
Preckwinkel, U., see Wengenmair, H.	99 (1996) 313	Uetsuka, H., see Watanabe, K.	99 (1996) 411
Prohaska, T., see Asikainen, T.	99 (1996) 91	constant and one in minute, and	27 (1770) 411
		Valden, M., N. Xiang, J. Pere and M. Pessa,	
Quintana, P., L. Veleva, W. Cauich, R.		Dissociative chemisorption of methane	
Pomes and J.L. Peña, Study of the com-		on clean and oxygen precovered Pt(111)	99 (1996) 83
position and morphology of initial stages		Van Wijk, R., P.C. Görts, C.H.M. Marée,	77 (1770) 63
of corrosion products formed on Zn		O.L.J. Gijzeman, F.H.P.M. Habraken	
plates exposed to the atmosphere of		and J.W. Geus, The oxidation of Cu	
southeast Mexico	99 (1996) 325	particles supported on oxidised Si(100)	
SOUTH BUT THE ABOV	77 (1770) 323	as studied by nuclear reaction analysis	
Rauschenbach, B., see Wengenmair, H.	99 (1996) 313	and ellipsometry	99 (1996) 127
Reniers, F., E. Silberberg, N. Roose and J.	27 (1970) 513	Van Wijk, R., C.H.M. Marée, O.L.J. Gijze-	77 (1990) 127
Vereecken, Study of the chemical bond-		man, F.H.P.M. Habraken and J.W. Geus,	
ing in tungsten carbide and chromium		18 O seekeese with the seketate design	
films by application of factor analysis		18 O-exchange with the substrate during	
on AES depth profiles	00 (1004) 270	¹⁸ O oxidation of Cu particles supported	00 (1004) 100
The state of the s	99 (1996) 379	on ¹⁶ O-oxidised Si(100)	99 (1996) 197
Ditale M see Asilysinan T			
Ritala, M., see Asikainen, T. Roose, N., see Reniers, F.	99 (1996) 91 99 (1996) 379	Vázquez, A. and F. Pedraza, High resolu- tion electron microscopy characteriza-	

99 (1996) 319
99 (1996) 229
99 (1996) 237
99 (1996) 83
99 (1996) 119
99 (1996) 21 99 (1996) 265
99 (1996) 205 99 (1996) 51

Ablation

function in the nucleation and early

stages of thin film growth, M. Tomellini

C2H4 and reaction of CO + H2 on the

well-dispersed FeOx/y-Al2O3 and

FeOx/TiO2(a) catalysts, W. Ji, Y. Chen,

by laser ablation, B. Hirschauer, S.

Söderholm, J. Paul and A.S. Flodström

Large area synthesis of thin alumina films

S. Shen, S. Li and H. Wang

FTIR study of adsorption of CO, NO and

Subject index

Annealing

Approach to in situ characterization of

AES of semi-insulating polycrystalline sili-

Zr-silicide formation during the epitaxial

ature, T. Koch and P. Ziemann

con layers, J. Liday, S. Tomek and J.

growth of Y-stabilized zirconia films on

Si(100) and its avoidance by ion beam

assisted deposition at a reduced temper-

GaAs semiconductor materials, K. Li, J.

Surface and interface analysis of GaSb/

99 (1996) 9

99 (1996) 51

polysilicon surfaces annealed by XeCl Large area synthesis of thin alumina films excimer laser, T. Nishibe, H. Mitby laser ablation, B. Hirschauer, S. suhashi, Y. Matsuura and Y. Kawakyu 99 (1996) 35 Söderholm, J. Paul and A.S. Flodström 99 (1996) 285 Atomic force microscopy Alkali metals XPS and AFM characterization of a vanadium oxide film on TiO₂(100) surface. Oxidation of a Si(001) surface mediated by G. Chiarello, R. Barberi, A. Amoddeo, repetitive adsorption/desorption cycles L.S. Caputi and E. Colavita 99 (1996) 15 of Cs: a metastable deexcitation spec-Approach to in situ characterization of troscopy study, K. Yamada and S. polysilicon surfaces annealed by XeCl Nishigaki 99 (1996) 21 excimer laser, T. Nishibe, H. Mit-99 (1996) 35 suhashi, Y. Matsuura and Y. Kawakyu AFM and STM studies on In2O3 and ITO Alloys thin films deposited by atomic layer epitaxy, T. Asikainen, M. Ritala, M. XPS study of carbon/inconel bilayers as a Leskelä, T. Prohaska, G. Friedbacher function of substrate bias, M.S. Aouadi, and M. Grasserbauer 99 (1996) 91 P.C. Wong and K.A.R. Mitchell 99 (1996) 319 A simulation study of multi-atom tips and Hydrogen adsorption on the Pt(111)($\sqrt{3}$ estimation of resolution in atomic force ×√3)R30°-Sn surface alloy studied by microscopy, S. Banerjee, M.K. Sanyal high resolution core level photoelectron and A. Datta 99 (1996) 255 spectroscopy, E. Janin, M. Björkqvist, Preparation of thin silver films on mica T.M. Grehk, M. Göthelid, C.-M. Pradier, studied by XRD and AFM, J.-D. Grun-U.O. Karlsson and A. Rosengren 99 (1996) 371 waldt, F. Atamny, U. Göbel and A. 99 (1996) 353 Baiker Aluminium oxide Auger electron spectroscopy Modelling of the particle size distribution

99 (1996) 67

99 (1996) 151

99 (1996) 285

Lin, A.T.S. Wee, K.L. Tan, Z.C. Feng		well-dispersed FeOx/γ-Al ₂ O ₃ and	
and J.B. Webb	99 (1996) 59	FeOx/TiO2(a) catalysts, W. Ji, Y. Chen,	
AES study of electron beam induced dam-		S. Shen, S. Li and H. Wang	99 (1996) 151
age on TiO2 surfaces, A.J.M. Mens and		Ru-Cu/ZSM5 catalysts: Characterization	
O.L.J. Giizeman	99 (1996) 133	by FT-IR spectroscopy, C. Crisafulli, S.	
18 O-exchange with the substrate during 18 O		Scirè, S. Minicò, R. Maggiore and S.	
oxidation of Cu particles supported on		Galvagno	99 (1996) 401
¹⁶ O-oxidised Si(100), R. van Wijk,		Infrared chemiluminescence study of the	22 (1220) 101
C.H.M. Marée, O.L.J. Gijzeman,		dynamics of catalytic oxidation of CO	
F.H.P.M. Habraken and J.W. Geus	99 (1996) 197	and HCOOH on Pd(111) and polycrys-	
CuCl growth on the reconstructed surface of	32 (1220) 121	talline Pd surfaces, K. Watanabe, H.	
(0001) haematite, Q. Guo, L. Gui and		Uetsuka, H. Ohnuma and K. Kunimori	99 (1996) 411
N. Wu	99 (1996) 229	Octsuka, H. Onnuma and K. Kullinkori	77 (1770) 411
	99 (1990) 229		
Study of the chemical bonding in tungsten		Catalysis	
carbide and chromium films by applica-		Cultiyala	
tion of factor analysis on AES depth			
profiles, F. Reniers, E. Silberberg, N.		High resolution electron microscopy charac-	
Roose and J. Vereecken	99 (1996) 379	terization of small Pt-Pd/SiO2 parti-	
Oxidation of ultrathin iron layers grown on		cles in oxide-reducing cycles, A.	
Cu(111), C. Ruby and J. Fusy	99 (1996) 393	Vázquez and F. Pedraza	99 (1996) 213
		Ru-Cu/ZSM5 catalysts: Characterization	77 (1770) 213
D:		by FT-IR spectroscopy, C. Crisafulli, S.	
Bismuth		Scirè, S. Minicò, R. Maggiore and S.	
			99 (1996) 401
Time-of-flight SIMS study of Bi-Mo selec-		Galvagno	99 (1990) 401
tive oxidation catalysts, L.T. Weng, P.		Infrared chemiluminescence study of the	
Bertrand, O. Tirions and M. Devillers	99 (1996) 185	dynamics of catalytic oxidation of CO	
bettime, of thiolis and M. Bernier	77 (1770) 103	and HCOOH on Pd(111) and polycrys-	
		talline Pd surfaces, K. Watanabe, H.	
Carbides		Uetsuka, H. Ohnuma and K. Kunimori	99 (1996) 411
Study of the chemical bonding in tungsten		Chemical vapour deposition	
carbide and chromium films by applica-		Chemical capour acposition	
tion of factor analysis on AES depth			
profiles, F. Reniers, E. Silberberg, N.		Surface composition of CVD-grown \alpha-SiC	
Roose and J. Vereecken	99 (1996) 379	layers - an XPS and LEED study, H.	
Roose and J. Vereecken	77 (1770) 377	Behner and R. Rupp	99 (1996) 27
		Application and properties of sub-mono-	
Carbon		molecular layers of silicon dioxide de-	
		posited under mild conditions, D.M.	
		Knotter	99 (1996) 99
Chemical, mechanical and electrical proper-		On the application of XPS to ceria films	77 (1770) 77
ties of CN _x -films produced by reactive		grown by MOCVD using a fluorinated	
sputtering and N+-implantation in car-		precursor, D. Chadwick, J. McAleese,	
bon films, N. Laidani, A. Miotello and		K. Senkiw and B.C.H. Steele	99 (1996) 417
J. Perrière	99 (1996) 273	K. Senkiw and B.C.H. Steele	99 (1990) 417
XPS study of carbon/inconel bilayers as a			
function of substrate bias, M.S. Aouadi,		Chromium	
P.C. Wong and K.A.R. Mitchell	99 (1996) 319	Caronium	
		X-ray photoelectron spectroscopy of Cr/	
Carbon monoxide		COOCH3 interfaces on self-assembled	
		monolayers of 16-mercaptohexade-	
CO adsorption and CO oxidation on		canoate, D.R. Jung and A.W. Czanderna	99 (1996) 161
Rh(100), A. Baraldi, L. Gregoratti, G.		Study of the chemical bonding in tungsten	27 (2770) 101
Comelli, V.R. Dhanak, M. Kiskinova		carbide and chromium films by applica-	
and R. Rosei	99 (1996) 1	tion of factor analysis on AES depth	
FTIR study of adsorption of CO, NO and	77 (1770)	profiles, F. Reniers, E. Silberberg, N.	
C_2H_4 and reaction of $CO + H_2$ on the		Roose and J. Vereecken	99 (1996) 379
2114 and reaction of CO 7 112 on the		Access and J. Verecenen	27 (1270) 317

Copper

- The oxidation of Cu particles supported on oxidised Si(100) as studied by nuclear reaction analysis and ellipsometry, R. van Wijk, P.C. Görts, C.H.M. Marée, O.L.J. Gijzeman, F.H.P.M. Habraken and J.W. Geus
- ¹⁸O-exchange with the substrate during ¹⁸O oxidation of Cu particles supported on ¹⁶O-oxidised Si(100), R. van Wijk, C.H.M. Marée, O.L.J. Gijzeman, F.H.P.M. Habraken and J.W. Geus
- Influence of oxygen on the mass diffusion of Ag on Cu(110): a laterally resolved photoemission study, U. Kürpick, G. Meister and A. Goldmann
- CuCl growth on the reconstructed surface of (0001) haematite, Q. Guo, L. Gui and N. Wu
- Diffusion barrier property of TaN between Si and Cu, T. Oku, E. Kawakami, M. Uekubo, K. Takahiro, S. Yamaguchi and M. Murakami
- Oxidation of ultrathin iron layers grown on Cu(111), C. Ruby and J. Fusy
- Ru-Cu/ZSM5 catalysts: Characterization by FT-IR spectroscopy, C. Crisafulli, S. Scirè, S. Minicò, R. Maggiore and S. Galvagno

Corrosion

Study of the composition and morphology of initial stages of corrosion products formed on Zn plates exposed to the atmosphere of southeast Mexico, P. Quintana, L. Veleva, W. Cauich, R. Pomes and J.L. Peña

Depth profiling

Study of the chemical bonding in tungsten carbide and chromium films by application of factor analysis on AES depth profiles, F. Reniers, E. Silberberg, N. Roose and J. Vereecken

Electrical properties

- Interface chemistry and electric characterisation of nickel metallisation on 6H-SiC, Ts. Marinova, V. Krastev, C. Hallin, R. Yakimova and E. Janzén
- 'Stable to unstable' transition in the (Cs, O) activation layer on GaAs (100) surfaces

with negative electron affinity in extremely high vacuum, S. Pastuszka, A.S. Terekhov and A. Wolf

99 (1996) 361

99 (1996) 393

99 (1996) 99

99 (1996) 213

99 (1996) 237

99 (1996) 265

99 (1996) 313

99 (1996) 325

99 (1996) 133

Electron diffraction

99 (1996) 127 Oxidation of ultrathin iron layers grown on Cu(111), C. Ruby and J. Fusy

Electron energy loss spectroscopy

99 (1996) 197 CuCl growth on the reconstructed surface of (0001) haematite, Q. Guo, L. Gui and N. Wu 99 (1996) 229

99 (1996) 221 Electron microscopy

- 99 (1996) 229

 Application and properties of sub-monomolecular layers of silicon dioxide deposited under mild conditions, D.M. Knotter
- 99 (1996) 265

 High resolution electron microscopy characterization of small Pt-Pd/SiO₂ particles in oxide-reducing cycles, A.
 - Vázquez and F. Pedraza

 Properties of radio frequency magnetron
 sputtered silicon dioxide films, W.-F.
- 99 (1996) 401

 Wu and B.-S. Chiou

 Diffusion barrier property of TaN between
 Si and Cu, T. Oku, E. Kawakami, M.

 Uekubo, K. Takahiro, S. Yamaguchi and
 M. Murakami
 - Photon and ion beam assisted deposition of titanium nitride, H. Wengenmair, J.W. Gerlach, U. Preckwinkel, B. Stritzker and B. Rauschenbach
- 99 (1996) 325

 Study of the composition and morphology of initial stages of corrosion products formed on Zn plates exposed to the atmosphere of southeast Mexico, P. Quintana, L. Veleva, W. Cauich, R. Pomes and J.L. Peña

Electron stimulated desorption

99 (1996) 379 AES study of electron beam induced damage on TiO₂ surfaces, A.J.M. Mens and O.L.J. Gijzeman

Ellipsometry

The oxidation of Cu particles supported on oxidised Si(100) as studied by nuclear reaction analysis and ellipsometry, R. van Wijk, P.C. Görts, C.H.M. Marée,

O.L.J. Gijzeman, F.H.P.M. Habraken and J.W. Geus	99 (1996) 127	phology during first stage heteroepitaxy of Si on Ge(001), D. Aubel, L. Kubler, J.L. Bischoff, L. Simon and D. Bolmont	99 (1996) 169
Enitam		J.L. Bischoff, L. Simon and D. Bolmont	99 (1990) 109
Epitaxy		Halogenides	
Zr-silicide formation during the epitaxial			
growth of Y-stabilized zirconia films on Si(100) and its avoidance by ion beam assisted deposition at a reduced temperature, T. Koch and P. Ziemann	99 (1996) 51	CuCl growth on the reconstructed surface of (0001) haematite, Q. Guo, L. Gui and N. Wu	99 (1996) 229
AFM and STM studies on In O and ITO	27 (1770) 31	Hydrocarbons	
thin films deposited by atomic layer epi- taxy, T. Asikainen, M. Ritala, M. Leskelä, T. Prohaska, G. Friedbacher and M. Grasserbauer	99 (1996) 91	X-ray photoelectron spectroscopy of Cr/ COOCH ₃ interfaces on self-assembled monolayers of 16-mercaptohexade-	
X-ray photoelectron diffraction investiga- tion of Ge segregation and film mor-		canoate, D.R. Jung and A.W. Czanderna	99 (1996) 161
phology during first stage heteroepitaxy of Si on Ge(001), D. Aubel, L. Kubler,		Hydrogen	
J.L. Bischoff, L. Simon and D. Bolmont	99 (1996) 169		
Evaporation		Interrupted-temperature programmed de- sorption of hydrogen over silica-sup- ported platinum catalysts: the distribu-	
		tion of activation energy of desorption	
Photon and ion beam assisted deposition of titanium nitride, H. Wengenmair, J.W. Gerlach, U. Preckwinkel, B. Stritzker		and the phenomena of spillover and re- verse spillover of hydrogen, M. Arai, M. Fukushima and Y. Nishiyama	99 (1996) 145
and B. Rauschenbach	99 (1996) 313	Hydrogen adsorption on the $Pt(111)(\sqrt{3})$	
Preparation of thin silver films on mica studied by XRD and AFM, JD. Grun- waldt, F. Atamny, U. Göbel and A.		× √3)R30°-Sn surface alloy studied by high resolution core level photoelectron spectroscopy, E. Janin, M. Björkqvist,	
Baiker	99 (1996) 353	T.M. Grehk, M. Göthelid, CM. Pradier, U.O. Karlsson and A. Rosengren	99 (1996) 371
C-llim min la		U.O. Kansson and A. Rosengten	77 (1770) 3/1
Gallium antimonide		Indium	
Surface and interface analysis of GaSb/			
GaAs semiconductor materials, K. Li, J.		AFM and STM studies on In2O3 and ITO	
Lin, A.T.S. Wee, K.L. Tan, Z.C. Feng		thin films deposited by atomic layer epi-	
and J.B. Webb	99 (1996) 59	taxy, T. Asikainen, M. Ritala, M.	
		Leskelä, T. Prohaska, G. Friedbacher and M. Grasserbauer	99 (1996) 91
Gallium arsenide		and 141. Oranier Detect	77 (1770) 71
		Infrared spectroscopy	
Surface and interface analysis of GaSb/			
GaAs semiconductor materials, K. Li, J. Lin, A.T.S. Wee, K.L. Tan, Z.C. Feng		FTIR study of adsorption of CO, NO and	
and J.B. Webb	99 (1996) 59	C_2H_4 and reaction of $CO + H_2$ on the	
'Stable to unstable' transition in the (Cs, O)		well-dispersed FeOx/γ-Al ₂ O ₃ and	
activation layer on GaAs (100) surfaces		FeOx/TiO ₂ (a) catalysts, W. Ji, Y. Chen, S. Shen, S. Li and H. Wang	99 (1996) 151
with negative electron affinity in ex-		FTIR study of adsorption of CO, NO and	99 (1990) 131
tremely high vacuum, S. Pastuszka, A.S. Terekhov and A. Wolf	99 (1996) 361	C_2H_A and reaction of $CO + H_2$ on the	
	99 (1990) 301	well-dispersed FeOx/γ-Al ₂ O ₃ and FeOx/TiO ₂ (a) catalysts, W. Ji, Y. Chen,	
Germanium		S. Shen, S. Li and H. Wang	99 (1996) 151
V ray photoelectron difference investiga		Properties of radio frequency magnetron sputtered silicon dioxide films, WF.	
X-ray photoelectron diffraction investiga- tion of Ge segregation and film mor-		Wu and BS. Chiou	99 (1996) 237
and the same of th			

Ru-Cu/ZSM5 catalysts: Characterization by FT-IR spectroscopy, C. Crisafulli, S. Scirè, S. Minicò, R. Maggiore and S.		CuCl growth on the reconstructed surface of (0001) haematite, Q. Guo, L. Gui and N. Wu	99 (1996) 229
Galvagno	99 (1996) 401	XPS study of carbon/inconel bilayers as a function of substrate bias, M.S. Aouadi,	99 (1990) 229
Interfaces		P.C. Wong and K.A.R. Mitchell Oxidation of ultrathin iron layers grown on	99 (1996) 319
Surface and interface analysis of GaSb/		Cu(111), C. Ruby and J. Fusy	99 (1996) 393
GaAs semiconductor materials, K. Li, J. Lin, A.T.S. Wee, K.L. Tan, Z.C. Feng and J.B. Webb	99 (1996) 59	Laser processing	
Ion bombardment		Approach to in situ characterization of polysilicon surfaces annealed by XeCl excimer laser, T. Nishibe, H. Mit-	
Photon and ion beam assisted deposition of titanium nitride, H. Wengenmair, J.W.		suhashi, Y. Matsuura and Y. Kawakyu Line shape study of Ba ions in laser pro- duced plasmas, R.A. Al-Wazzan, J.M.	99 (1996) 35
Gerlach, U. Preckwinkel, B. Stritzker and B. Rauschenbach	99 (1996) 313	Hendron and T. Morrow	99 (1996) 345
Ion implantation		Low energy electron diffraction	
Chemical, mechanical and electrical proper- ties of CN _x -films produced by reactive sputtering and N*-implantation in car-		CO adsorption and CO oxidation on Rh(100), A. Baraldi, L. Gregoratti, G. Comelli, V.R. Dhanak, M. Kiskinova	
bon films, N. Laidani, A. Miotello and J. Perrière	99 (1996) 273	and R. Rosei Surface composition of CVD-grown α-SiC layers—an XPS and LEED study, H.	99 (1996) 1
Ion scattering		Behner and R. Rupp CuCl growth on the reconstructed surface of (0001) haematite, Q. Guo, L. Gui and	99 (1996) 27
Application and properties of sub-mono- molecular layers of silicon dioxide de- posited under mild conditions, D.M.		N. Wu	99 (1996) 229
Knotter 18 O-exchange with the substrate during 18 O	99 (1996) 99	Luminescence	
oxidation of Cu particles supported on ¹⁰ O-oxidised Si(100), R. van Wijk, C.H.M. Marée, O.L.J. Gijzeman,		Infrared chemiluminescence study of the dynamics of catalytic oxidation of CO and HCOOH on Pd(111) and polycrys-	
F.H.P.M. Habraken and J.W. Geus Diffusion barrier property of TaN between Si and Cu, T. Oku, E. Kawakami, M.	99 (1996) 197	talline Pd surfaces, K. Watanabe, H. Uetsuka, H. Ohnuma and K. Kunimori	99 (1996) 411
Uekubo, K. Takahiro, S. Yamaguchi and M. Murakami	99 (1996) 265	Metals	
Photon and ion beam assisted deposition of titanium nitride, H. Wengenmair, J.W. Gerlach, U. Preckwinkel, B. Stritzker		Growth of oxide films on metal surfaces:	
and B. Rauschenbach	99 (1996) 313	transition from parabolic to linear kinet- ics, V.P. Zhdanov and P.R. Norton	99 (1996) 205
Iron		Methane	
FTIR study of adsorption of CO, NO and C_2H_4 and reaction of CO + H_2 on the well-dispersed $FeOx/\gamma$ -Al $_2O_3$ and		Dissociative chemisorption of methane on clean and oxygen precovered Pt(111),	
FeOx/TiO ₂ (a) catalysts, W. Ji, Y. Chen, S. Shen, S. Li and H. Wang	99 (1996) 151	M. Valden, N. Xiang, J. Pere and M. Pessa	99 (1996) 83

Mica Organic substances X-ray photoelectron spectroscopy of Cr/ Preparation of thin silver films on mica COOCH, interfaces on self-assembled studied by XRD and AFM, J.-D. Grunwaldt, F. Atamny, U. Göbel and A. monolayers of 16-mercaptohexadecanoate, D.R. Jung and A.W. Czanderna Baiker 99 (1996) 353 99 (1996) 161 Oxidation Molybdenum CO adsorption and CO oxidation on Time-of-flight SIMS study of Bi-Mo selec-Rh(100), A. Baraldi, L. Gregoratti, G. tive oxidation catalysts, L.T. Weng, P. Comelli, V.R. Dhanak, M. Kiskinova Bertrand, O. Tirions and M. Devillers 99 (1996) 185 and R. Rosei 99 (1996) 1 Oxidation of a Si(001) surface mediated by repetitive adsorption/desorption cycles Multilayers of Cs: a metastable deexcitation spectroscopy study, K. Yamada and S. XPS study of carbon/inconel bilayers as a 99 (1996) 21 Nishigaki function of substrate bias, M.S. Aouadi, The oxidation of Cu particles supported on 99 (1996) 319 P.C. Wong and K.A.R. Mitchell oxidised Si(100) as studied by nuclear reaction analysis and ellipsometry, R. Nickel van Wijk, P.C. Görts, C.H.M. Marée, O.L.J. Gijzeman, F.H.P.M. Habraken and J.W. Geus Interface chemistry and electric characteri-99 (1996) 127 Time-of-flight SIMS study of Bi-Mo selecsation of nickel metallisation on 6H-SiC, Ts. Marinova, V. Krastev, C. Hallin, R. tive oxidation catalysts, L.T. Weng, P. Yakimova and E. Janzén 99 (1996) 119 Bertrand, O. Tirions and M. Devillers 99 (1996) 185 18 O-exchange with the substrate during 18 O XPS study of carbon/inconel bilayers as a oxidation of Cu particles supported on function of substrate bias, M.S. Aouadi, ¹⁶O-oxidised Si(100), R. van Wijk, P.C. Wong and K.A.R. Mitchell 99 (1996) 319 C.H.M. Marée, O.L.J. Gijzeman, F.H.P.M. Habraken and J.W. Geus 99 (1996) 197 Nitrides Oxidation of ultrathin iron layers grown on Cu(111), C. Ruby and J. Fusy 99 (1996) 393 Diffusion barrier property of TaN between Infrared chemiluminescence study of the Si and Cu, T. Oku, E. Kawakami, M. dynamics of catalytic oxidation of CO Uekubo, K. Takahiro, S. Yamaguchi and and HCOOH on Pd(111) and polycrys-99 (1996) 265 M. Murakami talline Pd surfaces, K. Watanabe, H. Chemical, mechanical and electrical proper-Uetsuka, H. Ohnuma and K. Kunimori 99 (1996) 411 ties of CN,-films produced by reactive sputtering and N*-implantation in car-Oxides bon films, N. Laidani, A. Miotello and J. Perrière 99 (1996) 273 XPS and AFM characterization of a vanadium oxide film on TiO₂(100) surface, Nuclear reaction analysis G. Chiarello, R. Barberi, A. Amoddeo, L.S. Caputi and E. Colavita 99 (1996) 15 Growth of oxide films on metal surfaces: The oxidation of Cu particles supported on transition from parabolic to linear kinetoxidised Si(100) as studied by nuclear 99 (1996) 205 ics, V.P. Zhdanov and P.R. Norton reaction analysis and ellipsometry, R. CuCl growth on the reconstructed surface of van Wijk, P.C. Görts, C.H.M. Marée, (0001) haematite, Q. Guo, L. Gui and O.L.J. Gijzeman, F.H.P.M. Habraken 99 (1996) 229 99 (1996) 127 N. Wu and J.W. Geus 18 O-exchange with the substrate during 18 O oxidation of Cu particles supported on Oxygen 16 O-oxidised Si(100), R. van Wijk, C.H.M. Marée. O.L.J. Giizeman. Dissociative chemisorption of methane on

99 (1996) 197

clean and oxygen precovered Pt(111),

F.H.P.M. Habraken and J.W. Geus

M. Valden, N. Xiang, J. Pere and M. Pessa Influence of oxygen on the mass diffusion of Ag on Cu(110): a laterally resolved	99 (1996) 83	of Si on Ge(001), D. Aubel, L. Kubler, J.L. Bischoff, L. Simon and D. Bolmont ¹⁸ O-exchange with the substrate during ¹⁸ O oxidation of Cu particles supported on	99 (1996) 169
photoemission study, U. Kürpick, G. Meister and A. Goldmann 'Stable to unstable' transition in the (Cs, O) activation layer on GaAs (100) surfaces	99 (1996) 221	18 O-oxidised Si(100), R. van Wijk, C.H.M. Marée, O.L.J. Gijzeman, F.H.P.M. Habraken and J.W. Geus Influence of oxygen on the mass diffusion	99 (1996) 197
with negative electron affinity in ex- tremely high vacuum, S. Pastuszka, A.S. Terekhov and A. Wolf	99 (1996) 361	of Ag on Cu(110): a laterally resolved photoemission study, U. Kürpick, G. Meister and A. Goldmann CuCl growth on the reconstructed surface of	99 (1996) 221
Palladium		(0001) haematite, Q. Guo, L. Gui and N. Wu	99 (1996) 229
High resolution electron microscopy charac- terization of small Pt-Pd/SiO ₂ parti- cles in oxide-reducing cycles, A.		Adsorption and decomposition of hexameth- yldisiloxane on platinum: an XPS, UPS and TDS study, L. Colin, A. Cassuto, J.J. Ehrhardt, M.F. Ruiz-Lopez and D.	
Vázquez and F. Pedraza Infrared chemiluminescence study of the	99 (1996) 213	Jamois	99 (1996) 245
dynamics of catalytic oxidation of CO and HCOOH on Pd(111) and polycrys- talline Pd surfaces, K. Watanabe, H.		Large area synthesis of thin alumina films by laser ablation, B. Hirschauer, S. Söderholm, J. Paul and A.S. Flodström XPS study of carbon/inconel bilayers as a	99 (1996) 285
Uetsuka, H. Ohnuma and K. Kunimori	99 (1996) 411	function of substrate bias, M.S. Aouadi, P.C. Wong and K.A.R. Mitchell	99 (1996) 319
Photoelectron spectroscopy		The nature of the surface acidity of an- odised titanium: an XPS study using 1,2-diaminoethane, J. Marsh, L. Minel,	
CO adsorption and CO oxidation on Rh(100), A. Baraldi, L. Gregoratti, G. Comelli, V.R. Dhanak, M. Kiskinova and R. Rosei	99 (1996) 1	M.G. Barthés-Labrousse and D. Gorse Preparation of thin silver films on mica studied by XRD and AFM, JD. Grun- waldt, F. Atamny, U. Göbel and A.	99 (1996) 335
XPS and AFM characterization of a vana- dium oxide film on TiO ₂ (100) surface, G. Chiarello, R. Barberi, A. Amoddeo,		Baiker On the application of XPS to ceria films grown by MOCVD using a fluorinated	99 (1996) 353
L.S. Caputi and E. Colavita Surface composition of CVD-grown α-SiC layers – an XPS and LEED study, H.	99 (1996) 15	precursor, D. Chadwick, J. McAleese, K. Senkiw and B.C.H. Steele	99 (1996) 417
Behner and R. Rupp	99 (1996) 27	Platinum	
Surface and interface analysis of GaSb/ GaAs semiconductor materials, K. Li, J. Lin, A.T.S. Wee, K.L. Tan, Z.C. Feng		Modelling of the particle size distribution function in the nucleation and early	
and J.B. Webb Application and properties of sub-mono- molecular layers of silicon dioxide de-	99 (1996) 59	stages of thin film growth, M. Tomellini Dissociative chemisorption of methane on clean and oxygen precovered Pt(111),	99 (1996) 67
posited under mild conditions, D.M. Knotter	99 (1996) 99	M. Valden, N. Xiang, J. Pere and M. Pessa	99 (1996) 83
Interface chemistry and electric characteri- sation of nickel metallisation on 6H-SiC, Ts. Marinova, V. Krastev, C. Hallin, R.		Interrupted-temperature programmed de- sorption of hydrogen over silica-sup- ported platinum catalysts: the distribu-	
Yakimova and E. Janzén X-ray photoelectron spectroscopy of Cr/ COOCH ₃ interfaces on self-assembled monolayers of 16-mercaptohexade-	99 (1996) 119	tion of activation energy of desorption and the phenomena of spillover and re- verse spillover of hydrogen, M. Arai, M. Fukushima and Y. Nishiyama	99 (1996) 145
canoate, D.R. Jung and A.W. Czanderna X-ray photoelectron diffraction investiga- tion of Ge segregation and film mor-	99 (1996) 161	High resolution electron microscopy charac- terization of small Pt-Pd/SiO ₂ parti- cles in oxide-reducing cycles, A.	77 (1770) 143
phology during first stage heteroepitaxy		Vázquez and F. Pedraza	99 (1996) 213

Adsorption and decomposition of hexameth- yldisiloxane on platinum: an XPS, UPS and TDS study, L. Colin, A. Cassuto, J.J. Ehrhardt, M.F. Ruiz-Lopez and D.		Surface and interface analysis of GaSb/ GaAs semiconductor materials, K. Li, J. Lin, A.T.S. Wee, K.L. Tan, Z.C. Feng and J.B. Webb	99 (1996) 59
Jamois Hydrogen adsorption on the Pt(111)($\sqrt{3}$ $\times \sqrt{5}$)R30°-Sn surface alloy studied by	99 (1996) 245	Application and properties of sub-mono- molecular layers of silicon dioxide de- posited under mild conditions, D.M.	33 (1770) 37
high resolution core level photoelectron spectroscopy, E. Janin, M. Björkqvist, T.M. Grehk, M. Göthelid, CM. Pradier,	00 (1004) 271	Knotter Time-of-flight SIMS study of Bi-Mo selec- tive oxidation catalysts, L.T. Weng, P.	99 (1996) 99
U.O. Karlsson and A. Rosengren	99 (1996) 371	Bertrand, O. Tirions and M. Devillers	99 (1996) 185
Polymers		Semiconductors	
Surface study of cross-linking gradients in photopolymers by acoustic microscopy, F. Augereau, B. Cros and J.P. Marco	99 (1996) 293	Surface and interface analysis of GaSb/ GaAs semiconductor materials, K. Li, J. Lin, A.T.S. Wee, K.L. Tan, Z.C. Feng and J.B. Webb	99 (1996) 59
Pulsed laser deposition		and J.B. Webb	99 (1990) 39
Large area synthesis of thin alumina films by laser ablation, B. Hirschauer, S.		Silicides	
Söderholm, J. Paul and A.S. Flodström Line shape study of Ba ions in laser pro- duced plasmas, R.A. Al-Wazzan, J.M. Hendron and T. Morrow	99 (1996) 285 99 (1996) 345	Zr-silicide formation during the epitaxial growth of Y-stabilized zirconia films on Si(100) and its avoidance by ion beam	
	99 (1990) 343	assisted deposition at a reduced temper- ature, T. Koch and P. Ziemann	99 (1996) 51
Rhodium		Silicon	
CO adsorption and CO oxidation on		Sucon	
Rh(100), A. Baraldi, L. Gregoratti, G. Comelli, V.R. Dhanak, M. Kiskinova and R. Rosei	99 (1996) 1	AES of semi-insulating polycrystalline sili- con layers, J. Liday, S. Tomek and J. Breza	99 (1996) 9
Ruthenium		Oxidation of a Si(001) surface mediated by repetitive adsorption/desorption cycles of Cs: a metastable deexcitation spec-	
Ru-Cu/ZSM5 catalysts: Characterization by FT-IR spectroscopy, C. Crisafulli, S. Scirè, S. Minicò, R. Maggiore and S.		troscopy study, K. Yamada and S. Nishigaki Approach to in situ characterization of	99 (1996) 21
Galvagno	99 (1996) 401	polysilicon surfaces annealed by XeCl excimer laser, T. Nishibe, H. Mit-	
Scanning tunneling microscopy		suhashi, Y. Matsuura and Y. Kawakyu Zr-silicide formation during the epitaxial	99 (1996) 35
AFM and STM studies on In ₂ O ₃ and ITO thin films deposited by atomic layer epi- taxy, T. Asikainen, M. Ritala, M.		growth of Y-stabilized zirconia films on Si(100) and its avoidance by ion beam assisted deposition at a reduced temper-	
Leskelä, T. Prohaska, G. Friedbacher and M. Grasserbauer	99 (1996) 91	ature, T. Koch and P. Ziemann The oxidation of Cu particles supported on oxidised Si(100) as studied by nuclear	99 (1996) 51
Secondary ion mass spectrometry		reaction analysis and ellipsometry, R. van Wijk, P.C. Görts, C.H.M. Marée, O.L.J. Gijzeman, F.H.P.M. Habraken	
ToF-SIMS analysis of adsorbate/membrane interactions. I. Adsorption of dehydroabietic acid on poly(vinylidene fluoride), P. Spevack and Y. Deslandes	99 (1996) 41	and J.W. Geus X-ray photoelectron diffraction investiga- tion of Ge segregation and film mor- phology during first stage heteroepitaxy	99 (1996) 127

of Si on Ge(001), D. Aubel, L. Kubler,		waldt, F. Atamny, U. Göbel and A.	
J.L. Bischoff, L. Simon and D. Bolmont Diffusion barrier property of TaN between	99 (1996) 169	Baiker	99 (1996) 353
Si and Cu, T. Oku, E. Kawakami, M. Uekubo, K. Takahiro, S. Yamaguchi and		Sputter deposition	
M. Murakami	99 (1996) 265	Trailigide formation during the enitorial	
Sampling depth of total electron and fluo- rescence measurements in Si L- and K- edge absorption spectroscopy, M. Kas- rai, W.N. Lennard, R.W. Brunner, G.M.		Zr-silicide formation during the epitaxial growth of Y-stabilized zirconia films on Si(100) and its avoidance by ion beam assisted deposition at a reduced temper- ature, T. Koch and P. Ziemann	99 (1996) 51
Bancroft, J.A. Bardwell and K.H. Tan	99 (1996) 303	Properties of radio frequency magnetron sputtered silicon dioxide films, WF.	
Silicon carbide		Wu and BS. Chiou Chemical, mechanical and electrical proper-	99 (1996) 237
Surface composition of CVD-grown α-SiC layers – an XPS and LEED study, H.		ties of CN,-films produced by reactive sputtering and N*-implantation in car-	
Behner and R. Rupp Interface chemistry and electric characteri-	99 (1996) 27	bon films, N. Laidani, A. Miotello and J. Perrière	99 (1996) 273
sation of nickel metallisation on 6H-SiC, Ts. Marinova, V. Krastev, C. Hallin, R.		XPS study of carbon/inconel bilayers as a function of substrate bias, M.S. Aouadi,	
Yakimova and E. Janzén	99 (1996) 119	P.C. Wong and K.A.R. Mitchell	99 (1996) 319
Silicon oxide		Sulphur dioxide	
Application and properties of sub-mono- molecular layers of silicon dioxide de- posited under mild conditions, D.M.		High temperature SO ₂ retention by CaO, M.J. Muñoz-Guillena, A. Linares-Solano and C. Salinas-Martínez de Lecea	99 (1996) 111
Knotter 18 O-exchange with the substrate during 18 O oxidation of Cu particles supported on	99 (1996) 99	Tantalum	
¹⁶ O-oxidised Si(100), R. van Wijk, C.H.M. Marée, O.L.J. Gijzeman, F.H.P.M. Habraken and J.W. Geus High resolution electron microscopy charac- terization of small Pt-Pd/SiO, parti-	99 (1996) 197	Diffusion barrier property of TaN between Si and Cu, T. Oku, E. Kawakami, M. Uekubo, K. Takahiro, S. Yamaguchi and M. Murakami	99 (1996) 265
cles in oxide-reducing cycles, A. Vázquez and F. Pedraza	99 (1996) 213	Thermal desorption	
Properties of radio frequency magnetron sputtered silicon dioxide films, WF. Wu and BS. Chiou	99 (1996) 237	CO adsorption and CO oxidation on Rh(100), A. Baraldi, L. Gregoratti, G.	
Sampling depth of total electron and fluo- rescence measurements in Si L- and K- edge absorption spectroscopy, M. Kas-		Comelli, V.R. Dhanak, M. Kiskinova and R. Rosei High temperature SO ₂ retention by CaO,	99 (1996) 1
rai, W.N. Lennard, R.W. Brunner, G.M. Bancroft, J.A. Bardwell and K.H. Tan	99 (1996) 303	M.J. Muñoz-Guillena, A. Linares-Solano and C. Salinas-Martínez de Lecea Interrupted-temperature programmed de	99 (1996) 111
Silver		sorption of hydrogen over silica-sup- ported platinum catalysts: the distribu- tion of activation energy of desorption	
Influence of oxygen on the mass diffusion of Ag on Cu(110): a laterally resolved photoemission study, U. Kürpick, G.		and the phenomena of spillover and re- verse spillover of hydrogen, M. Arai, M. Fukushima and Y. Nishiyama	99 (1996) 145
Meister and A. Goldmann Wettability of native silver surfaces, M.A. Osman and B.A. Keller Preparation of thin silver films on mica	99 (1996) 221 99 (1996) 261	FTIR study of adsorption of CO, NO and C ₂ H ₄ and reaction of CO + H ₂ on the well-dispersed FeOx/γ-Al ₂ O ₃ and FeOx (TiO ₃) are less than the state of the	
studied by XRD and AFM, JD. Grun-		FeOx/TiO ₂ (a) catalysts, W. Ji, Y. Chen, S. Shen, S. Li and H. Wang	99 (1996) 151

Adsorption and decomposition of hexameth- yldisiloxane on platinum: an XPS, UPS and TDS study, L. Colin, A. Cassuto, J.J. Ehrhardt, M.F. Ruiz-Lopez and D. Jamois Thin films	99 (1996) 245	tion of factor analysis on AES depth profiles, F. Reniers, E. Silberberg, N. Roose and J. Vereecken On the application of XPS to ceria films grown by MOCVD using a fluorinated precursor, D. Chadwick, J. McAleese, K. Senkiw and B.C.H. Steele	99 (1996) 379 99 (1996) 417
,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,		T	
Surface composition of CVD-grown α-SiC layers – an XPS and LEED study, H. Behner and R. Rupp	99 (1996) 27	Time of flight techniques ToF-SIMS analysis of adsorbate/membrane	
Zr-silicide formation during the epitaxial growth of Y-stabilized zirconia films on Si(100) and its avoidance by ion beam	77(1770) 27	interactions. I. Adsorption of dehydroa- bietic acid on poly(vinylidene fluoride), P. Spevack and Y. Deslandes	99 (1996) 41
assisted deposition at a reduced temper- ature, T. Koch and P. Ziemann Modelling of the particle size distribution	99 (1996) 51	Time-of-flight SIMS study of Bi-Mo selec- tive oxidation catalysts, L.T. Weng, P. Bertrand, O. Tirions and M. Devillers	99 (1996) 185
function in the nucleation and early stages of thin film growth, M. Tomellini	99 (1996) 67	Tin	
AFM and STM studies on In ₂ O ₃ and ITO thin films deposited by atomic layer epi- taxy, T. Asikainen, M. Ritala, M. Leskelä, T. Prohaska, G. Friedbacher and M. Grasserbauer	99 (1996) 91	Hydrogen adsorption on the $Pt(111)(\sqrt{3} \times \sqrt{3})R30^{\circ}$ -Sn surface alloy studied by high resolution core level photoelectron spectroscopy, E. Janin, M. Björkqvist,	
Application and properties of sub-mono- molecular layers of silicon dioxide de- posited under mild conditions, D.M. Knotter	99 (1996) 99	T.M. Grehk, M. Göthelid, CM. Pradier, U.O. Karlsson and A. Rosengren	99 (1996) 371
X-ray photoelectron diffraction investiga- tion of Ge segregation and film mor- phology during first stage heteroepitaxy of Si on Ge(001), D. Aubel, L. Kubler, J.L. Bischoff, L. Simon and D. Bolmont	99 (1996) 169	Tin oxide AFM and STM studies on In ₂ O ₃ and ITO thin films deposited by atomic layer epitaxy, T. Asikainen, M. Ritala, M.	
Properties of radio frequency magnetron sputtered silicon dioxide films, WF. Wu and BS. Chiou	99 (1996) 237	Leskelä, T. Prohaska, G. Friedbacher and M. Grasserbauer	99 (1996) 91
Chemical, mechanical and electrical proper- ties of CN _x -films produced by reactive sputtering and N*-implantation in car-	77 (1770) 237	Titanium The nature of the surface acidity of an-	
bon films, N. Laidani, A. Miotello and J. Perrière Large area synthesis of thin alumina films	99 (1996) 273	odised titanium: an XPS study using 1,2-diaminoethane, J. Marsh, L. Minel, M.G. Barthés-Labrousse and D. Gorse	99 (1996) 335
by laser ablation, B. Hirschauer, S. Söderholm, J. Paul and A.S. Flodström Photon and ion beam assisted deposition of	99 (1996) 285	Titanium nitride	
titanium nitride, H. Wengenmair, J.W. Gerlach, U. Preckwinkel, B. Stritzker and B. Rauschenbach	99 (1996) 313	Photon and ion beam assisted deposition of titanium nitride, H. Wengenmair, J.W. Gerlach, U. Preckwinkel, B. Stritzker	
XPS study of carbon/inconel bilayers as a function of substrate bias, M.S. Aouadi, P.C. Wong and K.A.R. Mitchell	99 (1996) 319	and B. Rauschenbach	99 (1996) 313
Preparation of thin silver films on mica studied by XRD and AFM, JD. Grun-	77 (1770) 317	Titanium oxide	
waldt, F. Atamny, U. Göbel and A. Baiker Study of the chemical bonding in tungsten carbide and chromium films by applica-	99 (1996) 353	XPS and AFM characterization of a vana- dium oxide film on TiO ₂ (100) surface, G. Chiarello, R. Barberi, A. Amoddeo, L.S. Caputi and E. Colavita	99 (1996) 15

AES study of electron beam induced damage on TiO ₂ surfaces, A.J.M. Mens and O.L.J. Gijzeman	99 (1996) 133	Photon and ion beam assisted deposition of titanium nitride, H. Wengenmair, J.W. Gerlach, U. Preckwinkel, B. Stritzker	
FTIR study of adsorption of CO, NO and C ₂ H ₄ and reaction of CO + H ₂ on the well-dispersed FeOx/γ-Al ₂ O ₃ and FeOx/TiO ₂ (a) catalysts, W. Ji, Y. Chen, S. Shen, S. Li and H. Wang	99 (1996) 151	and B. Rauschenbach Study of the composition and morphology of initial stages of corrosion products formed on Zn plates exposed to the atmosphere of southeast Mexico, P.	99 (1996) 313
Tungsten		Quintana, L. Veleva, W. Cauich, R. Pomes and J.L. Peña Preparation of thin silver films on mica	99 (1996) 325
Study of the chemical bonding in tungsten carbide and chromium films by applica- tion of factor analysis on AES depth profiles, F. Reniers, E. Silberberg, N.		studied by XRD and AFM, JD. Grun- waldt, F. Atamny, U. Göbel and A. Baiker	99 (1996) 353
Roose and J. Vereecken	99 (1996) 379	X-ray scattering	
Vanadium		Investigation of the solid surface structural	
XPS and AFM characterization of a vana- dium oxide film on TiO ₂ (100) surface, G. Chiarello, R. Barberi, A. Amoddeo,		inhomogeneities by the 'combined' small-angle X-ray scattering and Hg porosimetry methods, L.I. Skatkov, P.G. Cheremskoy, V.P. Gomozov and B.I.	
L.S. Caputi and E. Colavita	99 (1996) 15	Bayrachny	99 (1996) 367
X-ray absorption		Yttrium	
Sampling depth of total electron and fluo- rescence measurements in Si L- and K- edge absorption spectroscopy, M. Kas- rai, W.N. Lennard, R.W. Brunner, G.M. Bancroft, J.A. Bardwell and K.H. Tan	99 (1996) 303	Zr-silicide formation during the epitaxial growth of Y-stabilized zirconia films on Si(100) and its avoidance by ion beam assisted deposition at a reduced temperature, T. Koch and P. Ziernann	99 (1996) 51
X-ray diffraction		-	
Zr-silicide formation during the epitaxial growth of Y-stabilized zirconia films on Si(100) and its avoidance by ion beam		Zinc Study of the composition and morphology	
assisted deposition at a reduced temper- ature, T. Koch and P. Ziemann X-ray photoelectron diffraction investiga- tion of Ge segregation and film mor-	99 (1996) 51	of initial stages of corrosion products formed on Zn plates exposed to the atmosphere of southeast Mexico, P. Quintana, L. Veleva, W. Cauich, R.	
phology during first stage heteroepitaxy of Si on Ge(001), D. Aubel, L. Kubler, J.L. Bischoff, L. Simon and D. Bolmont	99 (1996) 169	Pomes and J.L. Peña Zirconium	99 (1996) 325
Diffusion barrier property of TaN between Si and Cu, T. Oku, E. Kawakami, M. Uekubo, K. Takahiro, S. Yamaguchi and		Zr-silicide formation during the epitaxial	
M. Murakami Large area synthesis of thin alumina films by laser ablation, B. Hirschauer, S.	99 (1996) 265	growth of Y-stabilized zirconia films on Si(100) and its avoidance by ion beam assisted deposition at a reduced temper-	
Söderholm, J. Paul and A.S. Flodström	99 (1996) 285	ature, T. Koch and P. Ziemann	99 (1996) 51

